



# TIMESPOT

Consiglio di Sezione INFN Padova

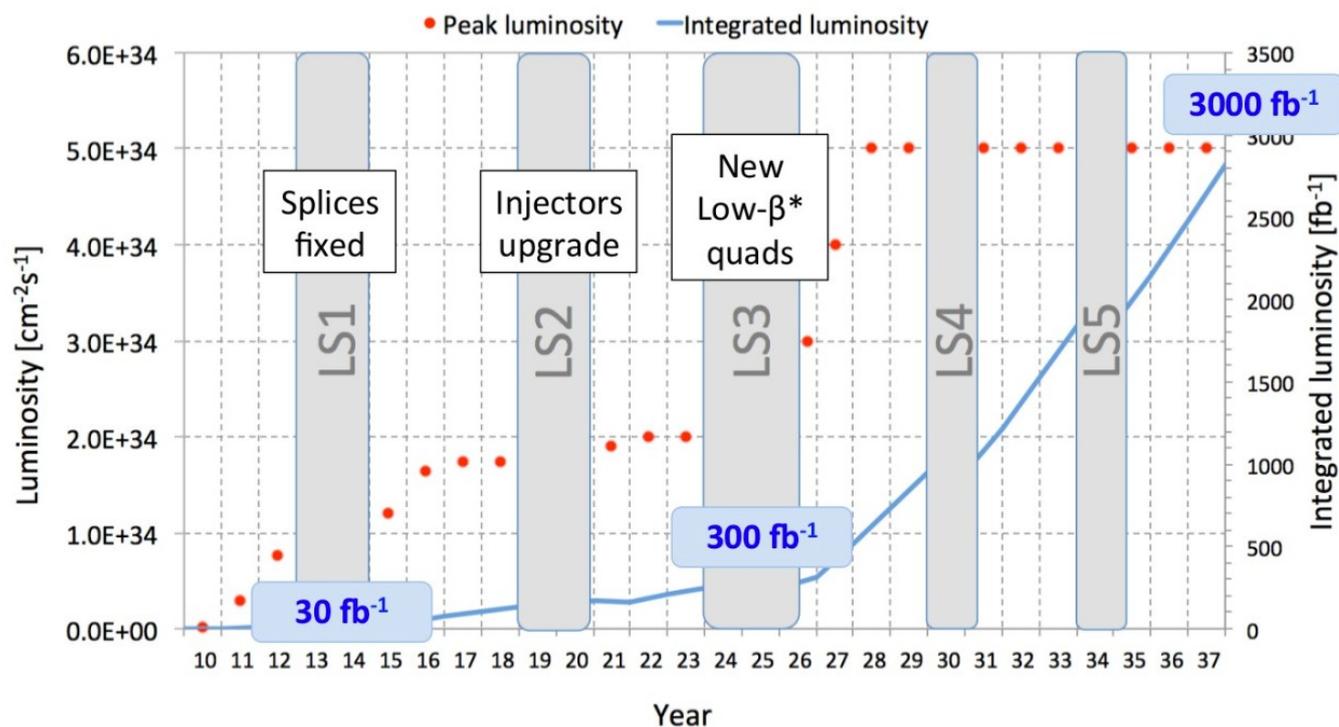
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Università di Padova and INFN

# Outline

- General Motivation
- Call GR5
- Activities 2017/2018
- Prospects 2018/2019

# General Motivation

- Fase di LHC con alta luminosita':  $5 \times 10^{34} \text{ cm}^{-2}\text{s}^{-1}$  con leveling (ATLAS and CMS) e  $1\text{-}2 \times 10^{34} \text{ cm}^{-2}\text{s}^{-1}$  per LHCb
  - Numero medio di interazioni visibili  $\sim 140$  ( $\sim 40$  per LHCb)
  - Precise tracking will be extremely challenging



# Tracking-Vertexing degradation of LHCb at LH-LHC

## Vertexing Performance degradation

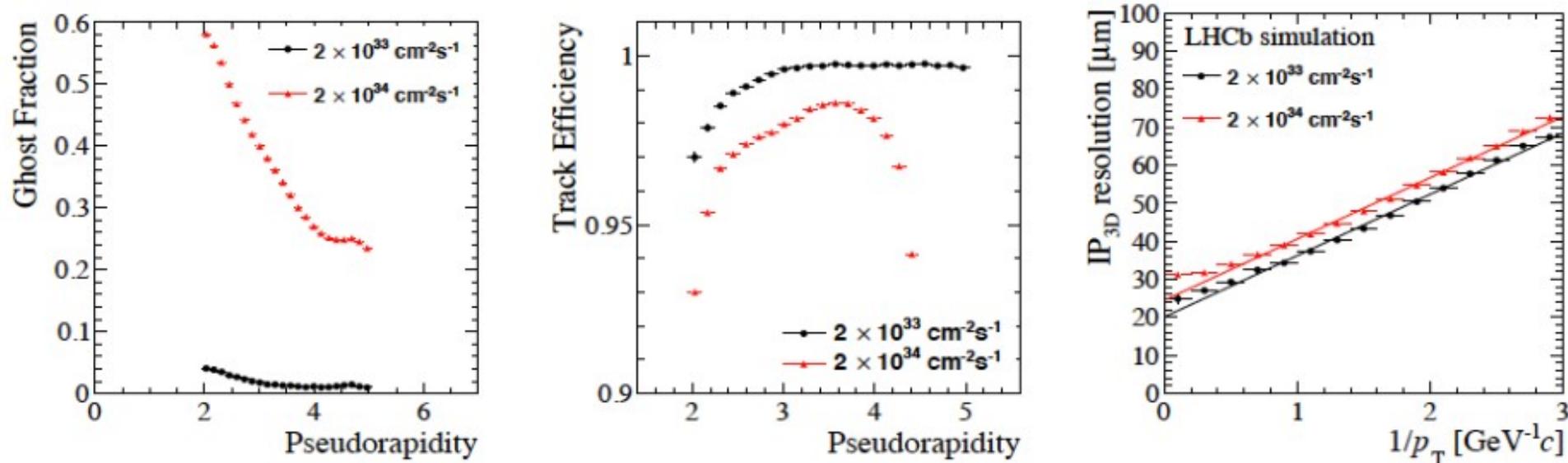
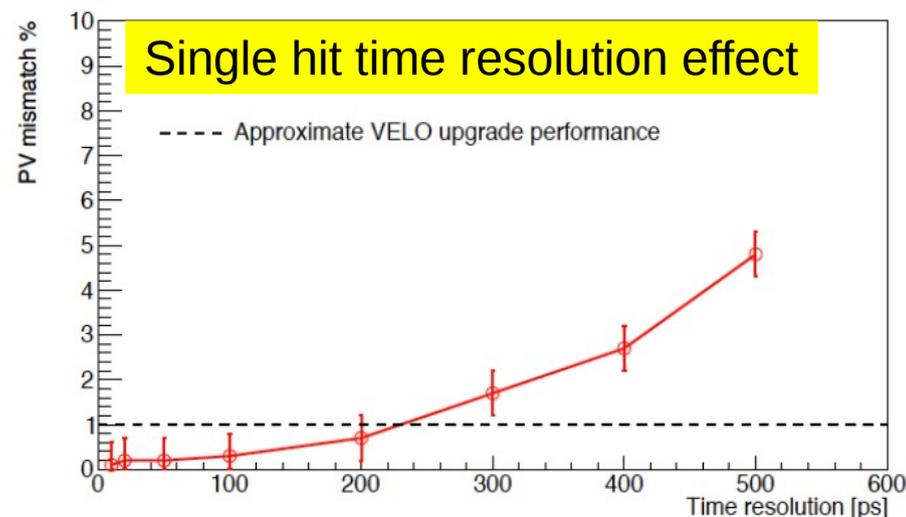
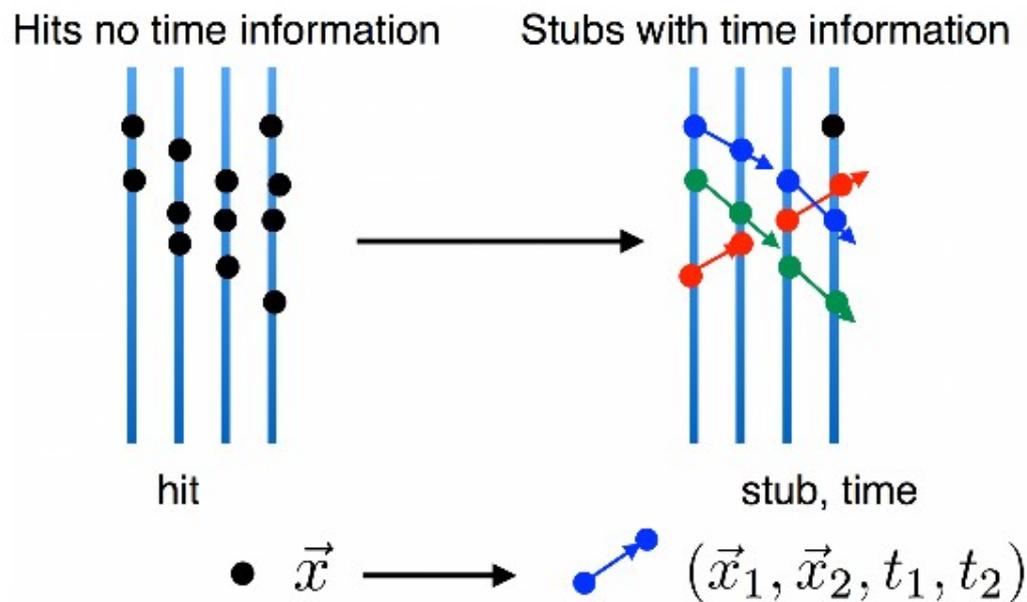


Fig. 1 – Performance of the Phase-I upgrade LHCb Vertex detector at Phase-II conditions [3].

# Tracking at LH-LHC

- L'uso di informazioni temporali precise puo' migliorare drammaticamente il sistema di tracciature nelle condizioni di alto pile-up in HL-LHC  
  - Semplificazione del pattern recognition e miglioramento della velocita' di ricostruzione
  - Riduzione delle tracce fantasma
- Bunch Crossing time  $\sim 250\text{ps}$



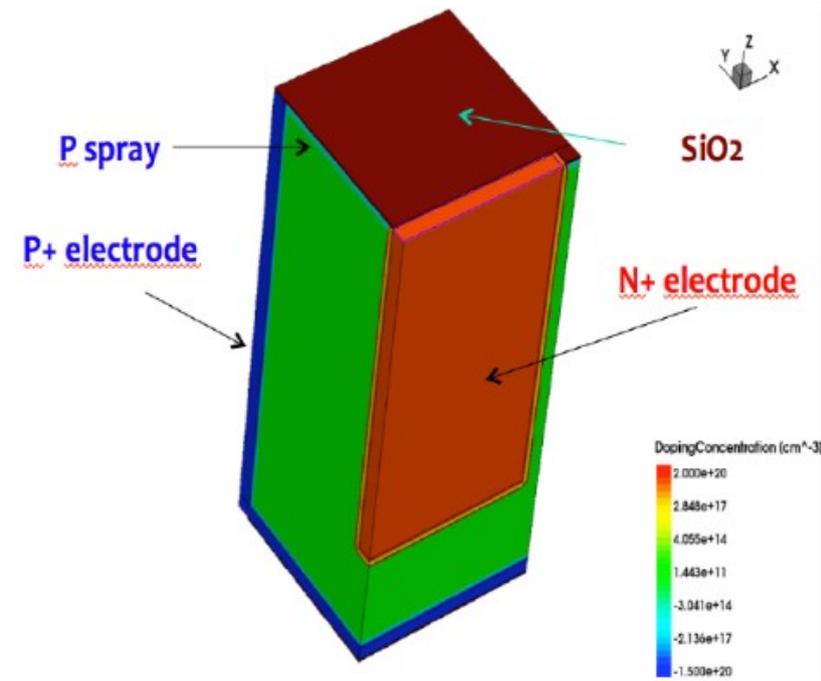
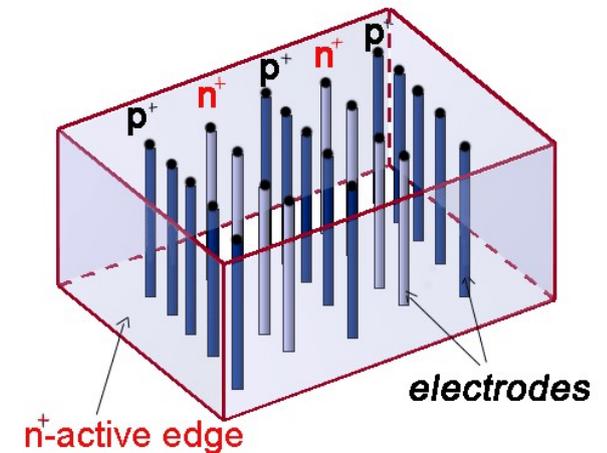
# TIMESPOT: TIME & Space real-time Operating Tracker

- Plan
  - Partendo da tecnologie disponibili sviluppare un sensore per microvertice con misura del tempo
  - Sviluppo di front end per misura precisa del tempo
  - Sviluppo di sistema di tracking real-time
  - Costruzione di un dimostratore
- System requirements
  - Space resolution: tens of  $\mu\text{m}$
  - Radiation hardness:  $> 10^{16}$  1 MeV  $n_{\text{eq}}/\text{cm}^2$  (sensors) and  $> 1$  Grad (electronics)
  - Time resolution:  $\leq 100$  ps
  - Real time track reconstruction algorithms and devices
- Progetto approvato nella CALL GR5 2017
  - Resp Naz A. Lai
  - Sedi: BO, CA, FE, FI, GE, MI, PD, PG, TIFPA, TO

# 3D sensors

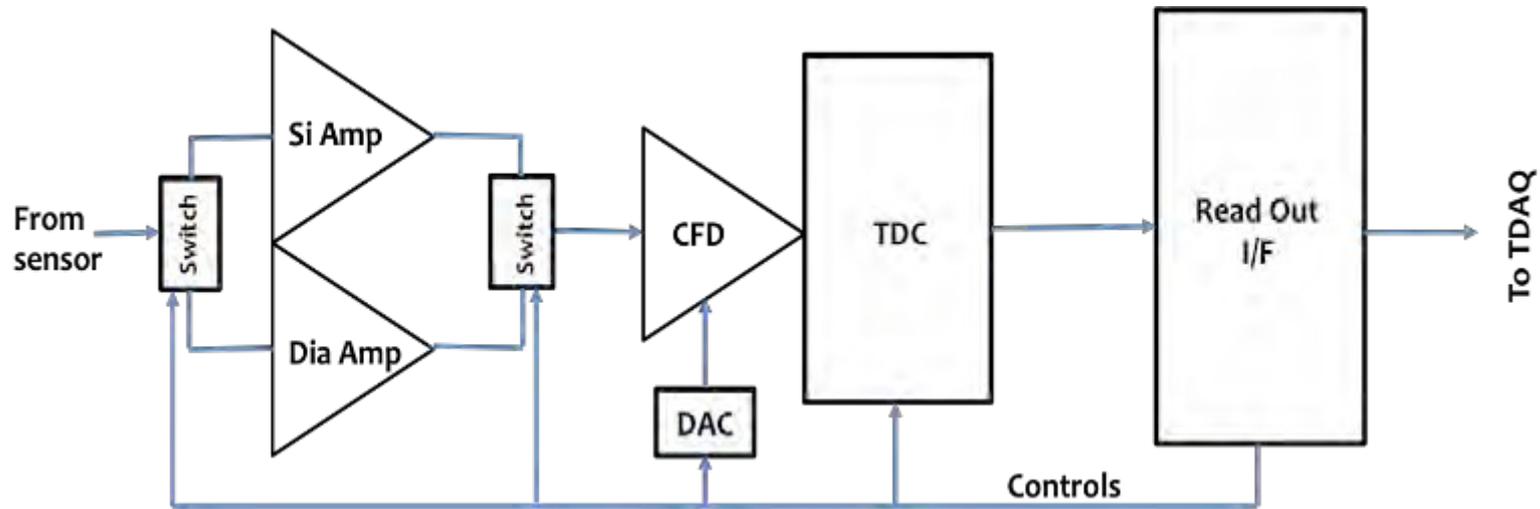
- Column 3D pixel sensors:
  - Good rad hardness
  - $I \sim v_d E_w$  (Ramo Theorem)
    - Non uniform signal
    - Signal position dependent
    - Not suitable for precise timing
- Si Trench 3D sensors
  - Uniform Weighting field
  - Good rad harness
  - Technologically more difficult
  - Bigger pixel capacitance
- Diamond graphitized sensors
  - Excellent rad hardness
  - Smaller signals
  - Technologically challenging

## 3D Silicon Pixel Sensors

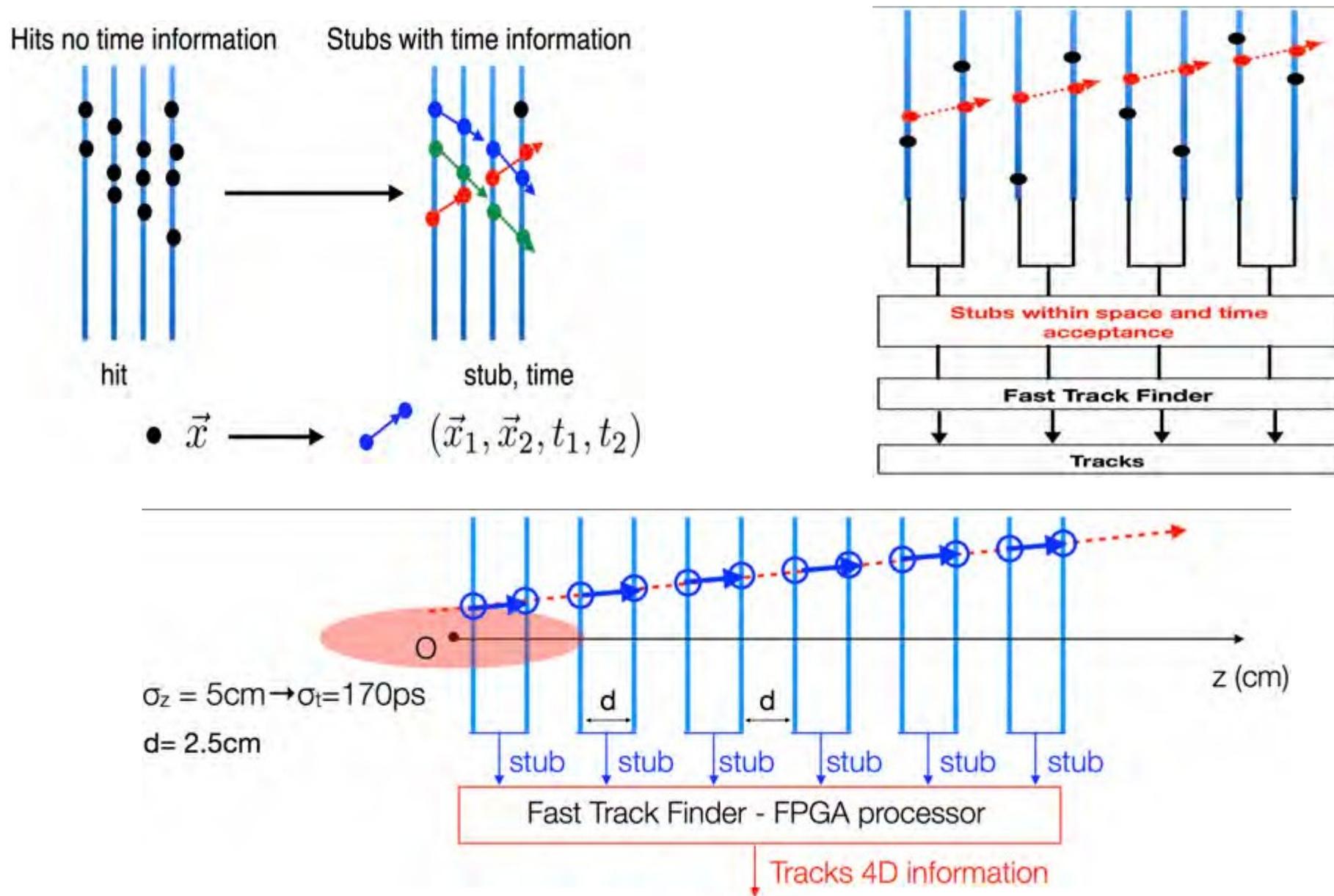


# Front-End

- Fast custom front end
  - Compromise between fast amplifier (noisier) and charge sensitive amplifier
    - Integrate the two for each channel



# Real-time reconstruction



# Activities

- WG1 [Cagliari, Ferrara, Genova, Padova, TIFPA, Torino.]
  - Sviluppo e caratterizzazione sensori 3D Silicio
- WG2 [Firenze, Genova, Perugia.]
  - Sviluppo e caratterizzazione sensori 3D Diamante
- WG3 [Cagliari, Milano, Torino]
  - Front-end
- WG4 [Bologna, Milano.]
  - Fast tracking
- WG5 [Bologna.]
  - DAQ
- WG6 [All]
  - Integration and demonstrator

Padova

Padova

# Attività previste a Padova

- Prima Produzione Strutture di test per sensori 3D da FBK prevista per settembre
- Test di caratterizzazione elettrica [2018]
  - Laboratorio Silici Padova
- Caratterizzazione sensori sotto fascio microbeam di legnaro [2018-2019]
  - Proposal per un esperimento con il microbeam di legnaro sottomessa
    - $E = 2\text{MeV}$  , penetrazione  $\sim 60\mu\text{m}$
    - Dimensione fascio = alcuni  $\mu\text{m}$
    - Tempo fascio = 5 giorni
  - Misura di efficienza di collezione di carica
  - Caratterizzazione dei segnali in funzione della posizione
  - Misura del danno da radiazione localizzato per irraggiamento con protoni
- Caratterizzazione sotto fascio di MIP [2019-2020]
  - Misura risoluzione temporale dei sensori in funzione della posizione

			Project Years												2018												2019												2020											
			Quarters			Q1				Q2				Q3				Q4				Q1			Q2			Q3			Q4																			
			Months												Months												Months												Months											
WP	Activity	Tasks	1	2	3	4	5	6	7	8	9	10	11	12	1	2	3	4	5	6	7	8	9	10	11	12	1	2	3	4	5	6	7	8	9	10	11	12												
1	3D silicon sensors for timing: development and characterization	Optimization studies and device modeling	█												█																																			
		Design & submission of 1st prototype							M1						█																																			
		Production of 1st prototype							█						█																																			
		Testbench characterization of 1st prot.							█						D4			█																																
		Design & submission of 2nd prototype							█						M6			█																																
		Production of 2nd prototype							█						█			█																																
		Testbench characterization of 2nd prot.							█						█			D9			█																													
2	3D diamond sensors for timing: development and characterization	Optimization studies and device modeling	█												█																																			
		Fabrication of 1st prototype							M2						█																																			
		Testbench characterization of 1st prot.							█						D2			█																																
		Fabrication of 2nd prototype							█						M5			█																																
		Testbench characterization of 2nd prot.							█						D8			█																																
		Fabrication of 3rd prototype							█						M9			█																																
3	Design and test of front-end IC for pixel readout	Testbench characterization of 3rd prot.							█						D11			█																																
		Design of front-end & test structure mini@sic	█												█																																			
		Design of TDC cell & readout IF mini@sic	█												█																																			
		Prod & packaging of 1st mini@sic prototype							M3						█																																			
		Test-bench preparation (test PCB)							█						█																																			
		Tests on front-end & test structure mini@sic							█						D5			█																																
		Tests on TDC cell & readout IF mini@sic							█						D6			█																																
		Design and submission of pixel IC							█						M7			█																																
		Production of pixel IC							█						█			█																																
		Tests of pixel IC							█						D12			█																																
		Design and submission of pixel IC (2nd version)							█						█			M14			█																													
4	Design and implementarion of fast tracking devices	Prod of pixel IC (2nd version)							█						D15			█																																
		Tests on 2nd version							█						█																																			
		Optimization of 4D algorithm	█						█						█																																			
		Definition of device architecture	█						█						█																																			
		Simulations at device level	█						█						M4												█																							
		Emulated tracks and DAQ/Retina boards	█						█						█												M13																							
		Emulated tracks at high rates and TDAQ/Track board	█						█						█												M15																							
5	Design and implementarion of high speed readout boards	Integration with demonstrator and test beam							█						█												D16																							
		Construction of 4 Pixel-ROD board for DAQ	█						█						█												D1																							
		Firmware optimization for TIMESPOT DAQ use	█						█						█																																			
		DAQ system for TIMESPOT lab tests	█						█						█												D3																							
		Design of new TDAQ board with real time track rec.	█						█						█												M8																							
		TDAQ/Track board production	█						█						█												█																							
		TDAQ/Track board tests	█						█						█												D13																							
6	System tests and integration, demonstrator tests	Integration with demonstrator and test beam							█						█												D16																							
		Organization of test beams and assembly (bonding) procedures	█						█						█																																			
		Rad. resistance tests on 1st sensor prototypes	█						█						█												M10																							
		Rad. resistance tests on 1st F/E ASIC	█						█						█												M11																							
		Sensor & FE assembly (mini@sic prototype)	█						█						█												D7																							
		Radiation tests on 1st F/E assembly	█						█						█												M12																							
		B-Bonding of pixel ASIC	█						█						█												D10																							
		Tests on sensor-bonded pixel IC	█						█						█												D14																							
		1-layer system test (sensor+F/E+TDAQ)	█						█						█												M16																							
		Full system demonstrator test	█						█						█												D16																							

# Anagrafica

- G.Collazuol 10%
- S.Gallorini 30%
- A.Lupato 30%
- S.Mattiazzo 10%
- G.Simi 20%
  - Tot 1FTE
- Acquisti 2018 [in corso]
  - Materiale per laboratorio silici
  - Elettronica di front end per lettura dei segnali delle strutture di test 3D
  - Sistema di trigger per microbeam
    - P-Terphenyl + SiPM readout
- Richieste 2019
  - 3kE consumo + 1kE inventariabil
    - Acquisto sistema di tag temporale per misure di timing
      - Cherenkov radiator + fast readout electronics
  - 2kE missioni per meeting interni, irraggiamenti, test beam